

<b>Notice of References Cited</b>	Application/Control No. 09/944,684	Applicant(s)/Patent Under Reexamination EDEN, GUY	
	Examiner LEYNNA T. HA	Art Unit 2135	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,108,656	08-2000	Durst et al.	707/10
*	B	US-5,060,165	10-1991	Schumacher et al.	700/213
*	C	US-7,084,994	08-2006	Koppich et al.	358/1.15
*	D	US-6,567,850	05-2003	Freishtat et al.	709/224
*	E	US-7,149,784	12-2006	Kitada et al.	709/207
*	F	US-6,856,415	02-2005	Simchik et al.	358/1.15
*	G	US-6,930,788	08-2005	Iwamoto et al.	358/1.15
*	H	US-7,028,012	04-2006	St. Vrain, Kent Carlyle	705/64
*	I	US-7,023,966	04-2006	Finnigan, Paul F.	379/88.02
*	J	US-6,401,097	06-2002	McCotter et al.	707/102
*	K	US-5,781,711	07-1998	Austin et al.	358/1.15
*	L	US-2002/0138759	09-2002	Dutta, Rabindranath	713/201
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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